Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/719,617	HANNAN ET AL.	
Examiner	Art Unit	
EDMUND H. LEE	1732	

SEARCHED				
Class	Subclass	Date	Examiner	
vpzaked	-	6/1406	WA	
				
				

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH I (INCLUDING SEAR		')
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vpland	6/1456	24